

Notice of References Cited

Application/Control No.

10/598,622

Applicant(s)/Patent Under
Reexamination
RIPPL ET AL.

Examiner

MAYA CLARK

Art Unit

3742

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,555,784 B2	04-2003	Iehisa et al.	219/121.76
*	B	US-6,100,497	08-2000	Maruyama et al.	219/121.63
*	C	US-5,267,683	12-1993	Hamada et al.	228/4.1
*	D	US-4,831,316	05-1989	Ishiguro et al.	700/254
*	E	US-RE34,597	05-1994	Akeel, Hadi A.	219/121.78
*	F	US-4,907,169	03-1990	Lovoi, Paul A.	700/259
*	G	US-6,486,436 B1	11-2002	Shah et al.	219/121.82
*	H	US-6,888,096 B1	05-2005	Hamada, Shiro	219/121.7
*	I	US-6,603,092 B2	08-2003	Briand et al.	219/121.64
*	J	US-5,245,682	09-1993	Ortiz, Jr., Angel L.	385/33
*	K	US-6,974,930 B2	12-2005	Jense, Willem Frederik	219/121.8
*	L	US-2008/0000886 A1	01-2008	Bell et al.	219/121.68
*	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.